

FCC PART 74
EUT SCHEMATIC DIAGRAMS
FOR
Guangzhou Bai Yun New Century Electronics Factory

Yong Tai Industrial Area,
Bai Yun, Guangzhou, China

FCC ID: PDMWM-2000

October 26, 2000

This Report Concerns: <input checked="" type="checkbox"/> Original Report	Equipment Type: Wireless Microphone – Household Appliances
Test Engineer: Victor Liu	
Test Date: October 3, 2000	
Reviewed By:	 John Y. Chan – Engineering Manager
Prepared By:	Bay Area Compliance Laboratory Corporation 230 Commercial Street, Suite 2 Sunnyvale, CA 94086 Tel: (408) 732-9162 Fax: (408) 732-9164

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1 - GENERAL INFORMATION

1.1 Product Description for Equipment Under Test (EUT)

The *Guangzhou Bai Yun New Century Electronics Factory*, FCC ID *PDMWM-2000* or the "EUT" as referred to in this report is a microphone which measures 9.25" L with diameter of 1.5".

1.2 Objective

This type approval report is prepared on behalf of *Guangzhou Bai Yun New Century Electronics Factory* in accordance with Part 74 Subpart H of the Federal Communication Commissions rules.

The objective of the manufacturer is to demonstrate compliance with FCC rules for peak output power, modulation characteristics, occupied bandwidth of emission, spurious emission, field strength of spurious radiation, frequency stability and line conduction.

1.3 Related Submittal(s)/Grant(s)

No Related Submittals

1.4 Test Methodology

All measurements contained in this report were conducted with ANSI C63.4 –1992, American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the range of 9 kHz to 40 GHz. All radiated and conducted emissions measurement was performed at Bay Area Compliance Laboratory, Corp. The radiated testing was performed at an antenna-to-EUT distance of 3 meters.

1.5 Test Facility

The Open Area Test site used by Bay Area Compliance Laboratory Corporation to collect radiated and conducted emission measurement data is located in the back parking lot of the building at 230 Commercial Street, Suite 2, Sunnyvale, California, USA.

Test sites at Bay Area Compliance Laboratory Corporation has been fully described in reports submitted to the Federal Communication Commission (FCC) and Voluntary Control Council for Interference (VCCI). The details of these reports has been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on February 11 and December 10, 1997 and Article 8 of the VCCI regulations on December 25, 1997. The facility also complies with the radiated and AC line conducted test site criteria set forth in ANSI C63.4-1992.

The Federal Communications Commission and Voluntary Control Council for Interference has the reports on file and is listed under FCC file 31040/SIT 1300F2 and VCCI Registration No.: C-674 and R-657. The test sites has been approved by the FCC and VCCI for public use and is listed in the FCC Public Access Link (PAL) database.

Additionally, Bay Area Compliance Laboratory Corporation is a National Institute of Standards and Technology (NIST) accredited laboratory, under the National Voluntary Laboratory Accredited Program (NVLAP). The scope of the accreditation covers the FCC Method - 47 CFR Part 15 - Digital Devices, IEC/CISPR 22: 1993, and AS/NZS 3548: Electromagnetic Interference - Limits and Methods of Measurement of Information Technology Equipment test methods under NVLAP Lab Code 200167-0.

1.6 Test Equipment List

Manufacturer	Description	Model	Serial Number	Cal. Due Data
HP	Spectrum Analyzer	8566B	2610A02165	12/6/00
HP	Spectrum Analyzer	8593B	2919A00242	12/20/00
HP	Amplifier	8349B	2644A02662	12/20/00
HP	Quasi-Peak Adapter	85650A	917059	12/6/00
HP	Amplifier	8447E	1937A01046	12/6/00
A.H. System	Horn Antenna	SAS0200/571	261	12/27/00
Com-Power	Log Periodic Antenna	AL-100	16005	11/2/01
Com-Power	Biconical Antenna	AB-100	14012	11/2/01
Solar Electronics	LISN	8012-50-R-24-BNC	968447	12/28/00
Com-Power	LISN	LI-200	12208	12/20/00
Com-Power	LISN	LI-200	12005	12/20/00
BACL	Data Entry Software	DES1	0001	12/20/00
Rohde & Schwarz	Signal Generator	SMIQ03B	1125.5555.03	7/10/2002
Rohde & Schwarz	I/Q Modulation Generator	AMIQ	1110.2003.02	8/10/2002

1.7 Equipment Under Test (EUT)

Manufacturer	Description	Model	Serial Number	FCC ID
Guangzhou Bai Yun New Century Electronics Factory	Microphone	WM-2000	None	PDMWM-2000

Appendix A – AUTHORIZATION LETTER

NEW CENTURY ELECTRONICS FTY.

July 22, 2000

FEDERAL COMMUNICATIONS COMMISSIONS
Authorization and Evaluation Division
7435 Oakland Mills Road0
Columbia, MD 21046

Subject: Agent Authorization

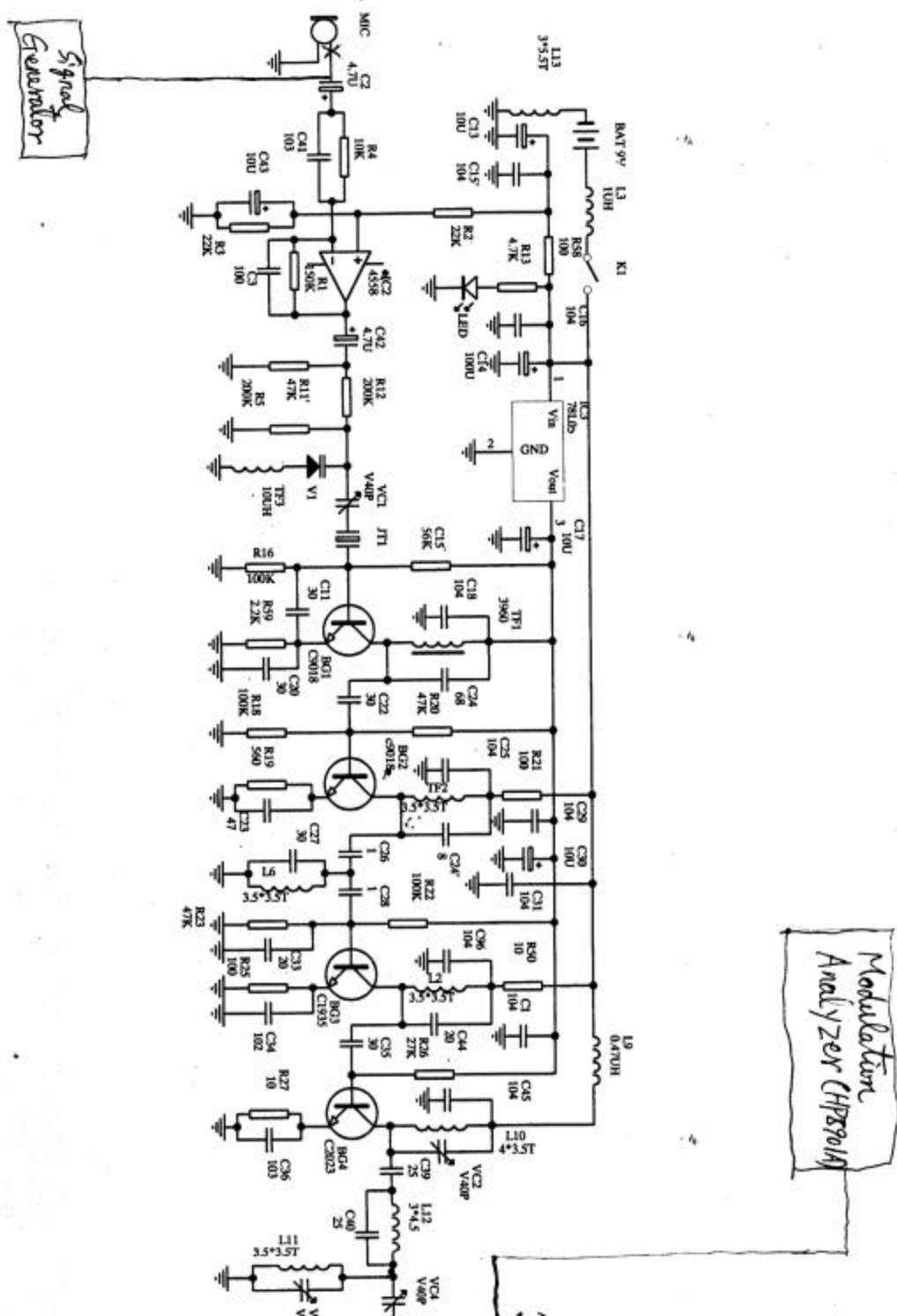
To whom it may concern:

NEW CENTURY ELECTRONICS FTY , hereby authorizes Bay Area Compliance Laboratory Corporation to act on its behalf in all matters relating to application for equipment authorization, including the signing of all documents relating to these matters. All acts carried out by Bay Area Compliance Laboratory Corporation on our behalf shall have the same effect as our own action.

Sincerely yours,

Xiaohua Chen(签名)

APPENDIX B – SCHEMATIC DIAGRAMS



BAI YUN NEW CENTURY ELECTRONICS FACTORY GUANGZHOU										
WM-2000 Transmitter LIST				FILE NUMBER: BM-0540-01				The A version the 1th page		
number	code	name	specification	position		quantity	remarks	change		
1		circuit board	112×25mm	WM-2000A1		1				
2	RT1G151J	resistance	RT-0.0625-150 Ω $\pm 5\%$	R18		1				
3	RT1G102J	resistance	RT-0.0625-10K Ω $\pm 5\%$	R24		1				
4	RT1G103J	resistance	RT-0.0625-15K Ω $\pm 5\%$	R23		1	15K use in green MIC			
5	RT1G153J		RT-0.0625-10K Ω $\pm 5\%$							
6	RT1G223J	resistance	RT-0.0625-22K Ω $\pm 5\%$	R22,R26		2				
7	RT1G473J	resistance	RT-0.0625-47K Ω $\pm 5\%$	R27,R20		2				
8	RT1G104J	resistance	RT-0.0625-56K Ω $\pm 5\%$	R1		1				
9	RT1G104J	resistance	RT-0.0625-100K Ω $\pm 5\%$	R21,R25		2				
10	CC505R0K	ceramic C	CC-50-5P $\pm 10\%$	C25		1				
11	CC50100K	ceramic C	CC-50-10P $\pm 10\%$	C10		1				
12	CC50150K	ceramic C	CC-50-15P $\pm 10\%$	C13		1	use in red LED			
13	CC50180K	ceramic C	CC-50-18P $\pm 11\%$	C13		1	use in green LED			
14	CC50180K	ceramic C	CC-50-18P $\pm 10\%$	C16		1				
15	CC50250K	ceramic C	CC-50-25P $\pm 11\%$	C15		1				
16	CC50350K	ceramic C	CC-50-35P $\pm 10\%$	C26		1				
17	CC50330K	ceramic C	CC-50-39P $\pm 11\%$	C9		1				
18	CC50400K	ceramic C	CC-50-40P $\pm 10\%$	C6		1				
19	CC50820K	ceramic C	CC-50-102P $\pm 10\%$	C12,C20		2				
20	CC50101K	ceramic C	CC-50-100P $\pm 10\%$	C30		1				
21	CC50502Z	ceramic C	CC-50-502P $\pm 80\%-20\%$	C21		1				
22	CC50104Z	ceramic C	CC-50-104P $\pm 80\%-20\%$	C4,C14,C19,C22,C23,C29		6				
23		modulate C	V30P	VC1		1	can be instead of 20P,40P			
24	CD10475M	electrolytic C	CD-10-4.7 μ F $\pm 20\%$	C5		1	diameter $\leq \phi 5\text{mm}$			
25	CD10106M	electrolytic C	CD-10-10 μ F $\pm 20\%$	C28,C24,C18		3	diameter $\leq \phi 5\text{mm}$			
26	CD10107M	electrolytic C	CD-10-100 μ F $\pm 20\%$	C17		1				
27		LED	$\phi 3\text{mm}$ (red or green)			1	on NOTE 2			
28		transistor	9014	BG3		1				
29		transistor	9018	BG1,BG2,BG4		3	KEC			
30		IC	78L05	IC2		1				
31	LG24R47M	hue circle inductance	LGA0204-R47M	L9,JP4		2				
32	LG24R2M	hue circle inductance	LGA0204-2R2M	R12		1				
33		hollow yoke	SC-0.6×3×5.5T-AW	L1,C5		2				
34		hollow yoke	SC-0.6×3×9.5T-AW	L6		1				
35		hollow yoke	SC-0.6×4×3.5T-AW	L2,L3		2				
36		hollow yoke	SC-0.6×3×4.5T-AW	L4		1	use in red MIC			
37		hollow yoke	SC-0.6×3×3.5T-AW	L4		1	use in green MIC			
38		MidF transforme	SW1	TF1		1				
39		switch	SS22H02-G6	K2		1				
40		jumper wires	$\Phi 0.5 \times 5\text{mm}$	JP1,JP2		1				
41		jumper wires	$\Phi 0.5 \times 5\text{mm}$	JP3		1				
							producer	<i>李工</i>	2008.8.17	
							examinant	<i>王工</i>	2008.8.17	
change	quantity	number	sign	date	change	quantity	number	sign	date	ratifier

